

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/659,276	NAKANISHI, YUTAKA
	Examiner	Art Unit
	Tuan H. Le	2622

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor name search	11/15/2006	TL
US-PGPUB,USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	11/15/2006	TL
INSPEC (same search key as in EAST)	11/15/2006	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner